Search Notes

Application/Control No.	Applicant(s)/Patent und Reexamination	ler
10/528,837	YAMAUCHI, AKIRA	
Examiner	Art Unit	
Michael Aboagye	1793	

	SEARCHED			
Class	Subclass	Date	Examiner	
228	203,205 219,218	10/16/2007	AM	
228	44.3 43	10/16/2007	АМ	
156	580 580.1	10/16/2007	AM	
156	345.29	10/16/2007	АМ	
134	1,1.1 1.2	10/16/2007	AM	
		,		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
-			

SEARCH I (INCLUDING SEAR)
	DATE	EXMR
ventor search	10/16/2007	AM
ast:Keywords search, lass 29 with keywords	10/16/2007	АМ